Tota	l No.	of Questions : 6]	SEAT No.:			
P 5	860		[Total No. of Pages : 2			
	BE/Insem/Oct604					
B.E.(IT)						
Software Testing & Quality Assurance						
(Semester - I) (Elective- II)						
(2015 Pattern)						
Time	e:1 H	lour]	[Max. Marks :30			
Insti	ructio	ns to the candidates:				
	1)	Answers. Q.1 or Q.2, Q.3 or Q.4, Q.5 or Q.6.				
	<i>2)</i>	Neat diagrams must be drawn wherever neces	sary and.			
	3)	Figures to the right side indicate full marks.	.,,			
	4)	Assume Suitable data if necessary.				
Q1)	a)	Explain Software Testing Life Cycle Phases	[6]			
	b)	Define the following terms.	[4]			
		i) Fault ii) Test bed				
		iii) Test Case iv) Software	e Quality			
()2)	2)	Evulain Defeat Life cole	[6]			
$Q^{2}$	a)	Explain Defect Life cycle.	[6]			
	b)	Explain V model of testing.	[4]			
		₩,				
Q3)	a)	Explain Control Flow Graph and Draw a cont code.	rol flow graph for following [6]			
	/* pos_sum finds the sum of all positive numbers (greater than zero) stored in an integer array a. Input parameters are num_of_entries, an integer, and a, an array of integers with num_of_entries elements. The output parameter is the integer sum*/					
		i) Pos_sum(a,num_of_entries, sum)	70.			
		ii) $sum = 0$	o.*			
		iii) inti=1	Р.Т.О.			

	iv)	while (i < num_of_entries)	
	v)	if a $[i] > 0$	
	vi)	sum=sum+a[i]	
	vii)	endif i=i+1 end while	
	viii)	end pos_sum	
b	) Exp	plain configuration testing and its objectives.	[4]
<b>2</b> ()	-6	OR	1 10
<b>Q4)</b> a	_	blain the steps in developing test cases with a cause-and-effect grap	
b	) Giv	ve difference between black box testing and white box testing.	[4]
<b>Q5)</b> a)	) Exp	plain Taguchi Quality Loss Function.	[6]
b	) Wri	ite short note on FMEA.  OR	[4]
<b>Q6)</b> a)	) Exp	olain Six Sigma Life cycle.	[6]
b	) Ехр	plain Defect removal Efficiency with an example.	[4]